

Notice of References Cited

Application/Control No.

10/511,313

Applicant(s)/Patent Under
Reexamination
SHIOKAWA ET AL.

Examiner

Devin Oakes

Art Unit

4185

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.